

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OYAKE ET AL.	
		Examiner Martin J Angebrannndt	Art Unit 1756	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,609,614	09-1986	Pampalone et al.	430/323
	C	US-6,465,149	10-2002	Kamijima et al.	430/270.1
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	U	Jenkins et al., 'Fundamentals of Optics', (1976) pp. 655
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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